

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components,

Assemblies, Related Materials and Processes For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity

Approved Process

IECQ Certificate No.: IECQ-L ULTW 16.0001

CB Certificate No.: 50600079 ITL

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Appendix-1 (50600079 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Hot-Carrier-Induced Degradation Under DC Stress (HCI)	JESD28, JESD60
Negative Bias Temperature Instabilities (NBTI)	JESD90
High Temperature Reverse Bias (HTRB)	JESD22A-108

June Nong

Technical Reviewer of DQS:

Date: 4/22/2020

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